

## Qualification Results Summary LTC6810-1/-2

LTC6810-1/-2 Reliability Report Summary			
TEST	SPECIFICATION	SAMPLE SIZE	RESULTS
Highly Accelerated Stress Test (HAST)*	JEDEC <i>JESD22-A101</i>	<b>3*77</b>	<b>Pass</b>
Temperature Cycle (TC)*	JEDEC <i>JESD22-A104</i>	<b>3*77</b>	<b>Pass</b>
Autoclave (AC)*	JEDEC <i>JESD22-A102</i>	<b>3*77</b>	<b>Pass</b>
High Temperature Storage Life (HTSL)	JEDEC <i>JESD22-A103</i>	<b>1*45</b>	<b>Pass</b>
High Temperature Operating Life (HTOL)	JEDEC <i>JESD22-A108</i>	<b>3*77</b>	<b>Pass</b>
Early Life Failure Rate (ELFR)	AEC-Q100-008	<b>3*800</b>	<b>Pass</b>
Latch-Up	JEDEC <i>JESD78</i>	<b>1*5</b>	<b>Pass</b>
Electrostatic Discharge <i>Field-Induced Charged Device Model</i>	JEDEC <i>JESD22-C101</i>	<b>3/voltage</b>	<b>Pass</b>
Electrostatic Discharge <i>Human Body Model</i>	ESDA/JEDEC <i>JS-001</i>	<b>3/voltage</b>	<b>Pass</b>

\* Preconditioned per JEDEC/IPC J-STD-020